

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No. 10/232,295
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Inventor Warren M. Farnworth et al.
Assignee Micron Technology, Inc.
Priority Group Art Unit 2829
Priority Examiner R. Kobert
Attorney's Docket No. MI22-2524
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability
and Method of Forming Apparatus for Testing Semiconductor Circuitry for
Operability

PRELIMINARY AMENDMENT

To: Mail Stop Patent Application
Commissioner for Patents
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Sir:

This is a preliminary amendment accompanying a Request for Divisional Application for the above-entitled patent application. Prior to examining the application, please enter the following amendments.

AMENDMENTS

Underlines indicate insertions and ~~strikeouts~~ indicate deletions.